

NIKO-SEM

P-Channel Enhancement Mode Field Effect Transistor

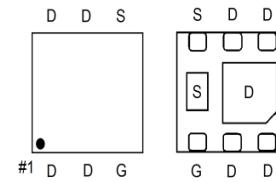
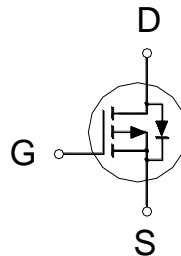
PB5B5BX

PDFN 2x2S

Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-20V	22mΩ	-7.9A



G : GATE
D : DRAIN
S : SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current	I_D	-7.9	A
		-6.3	
Pulsed Drain Current ¹	I_{DM}	-32	
Power Dissipation	P_D	2.2	W
		1.4	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		57	°C/W

¹Pulse width limited by maximum junction temperature.²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper.**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.65	-0.9	-1.2	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 12V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -16V, V_{GS} = 0V$			-1	μA
		$V_{DS} = -10V, V_{GS} = 0V, T_J = 55^\circ\text{C}$			-10	
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = -2.5V, I_D = -2\text{A}$		24	35	$\text{m}\Omega$
		$V_{GS} = -4.5V, I_D = -2.5\text{A}$		17.5	25	
		$V_{GS} = -10V, I_D = -2.5\text{A}$		14.8	22	
Forward Transconductance ¹	g_{fs}	$V_{DS} = -10V, I_D = -2.5\text{A}$		17		S

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DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = -10V, f = 1MHz$		1325		pF
Output Capacitance	C_{oss}			188		
Reverse Transfer Capacitance	C_{rss}			168		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		10		Ω
Total Gate Charge ²	Q_g	$V_{GS} = -10V, V_{DS} = -10V, I_D = -2.5A$		35		nC
Gate-Source Charge ²	Q_{gs}			1.4		
Gate-Drain Charge ²	Q_{gd}			5.2		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = -10V$ $I_D \approx -2.5A, V_{GEN} = -10V, R_G = 6\Omega$		21		nS
Rise Time ²	t_r			16		
Turn-Off Delay Time ²	$t_{d(off)}$			62		
Fall Time ²	t_f			36		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				-1.8	A
Forward Voltage ¹	V_{SD}	$I_F = -2.5A, V_{GS} = 0V$			-1.2	V
Reverse Recovery Time	t_{rr}	$I_F = -2.5A, dI_F/dt = 100A / \mu S$		41		nS
Reverse Recovery Charge	Q_{rr}			26		nC

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

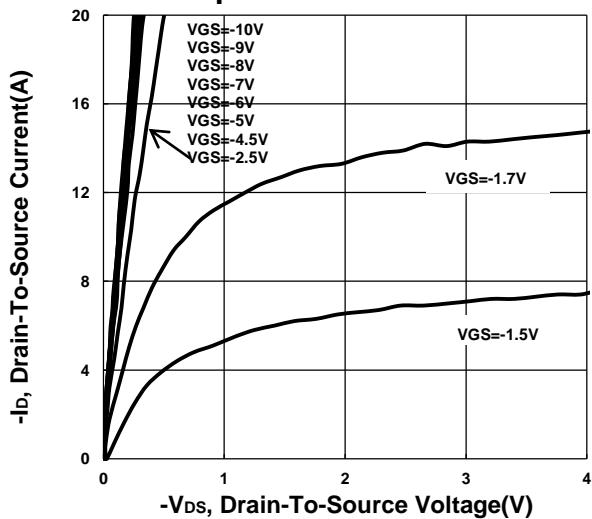
²Independent of operating temperature.

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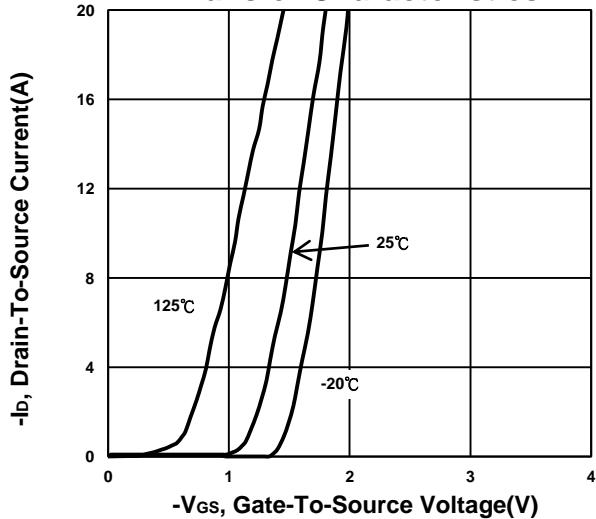
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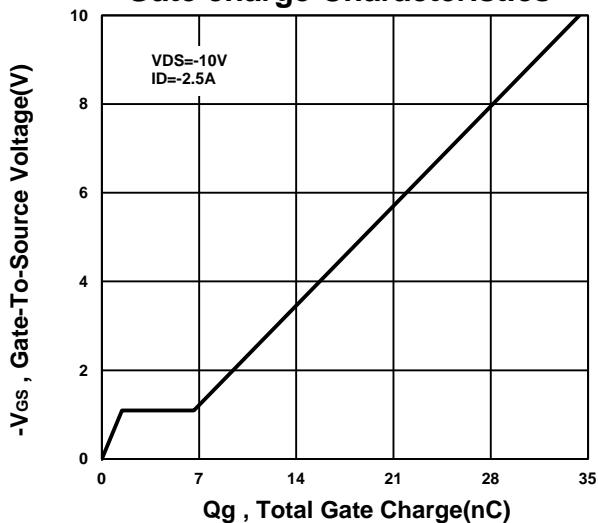
Output Characteristics



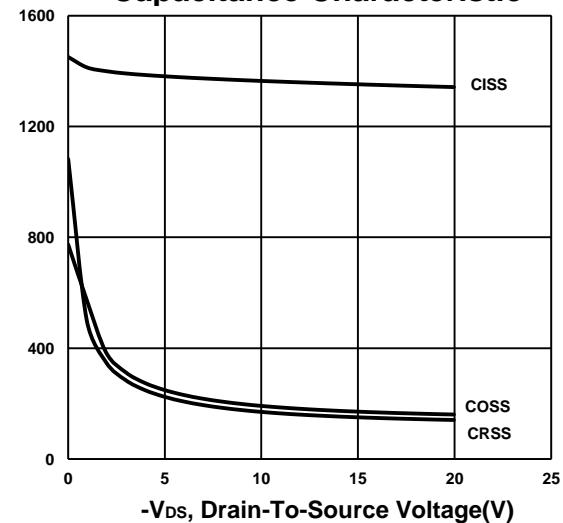
Transfer Characteristics



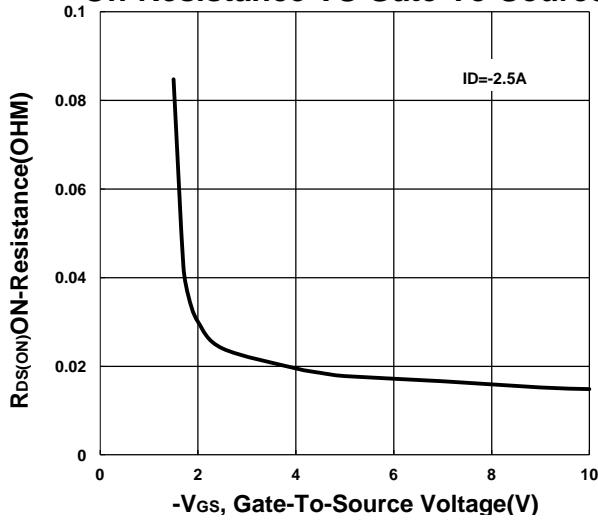
Gate charge Characteristics



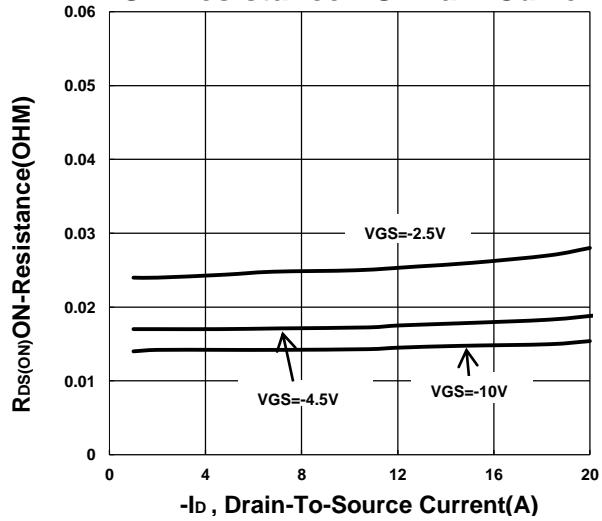
Capacitance Characteristic

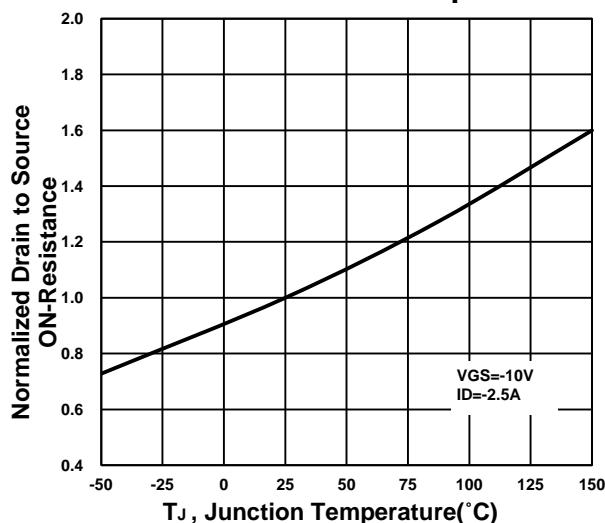
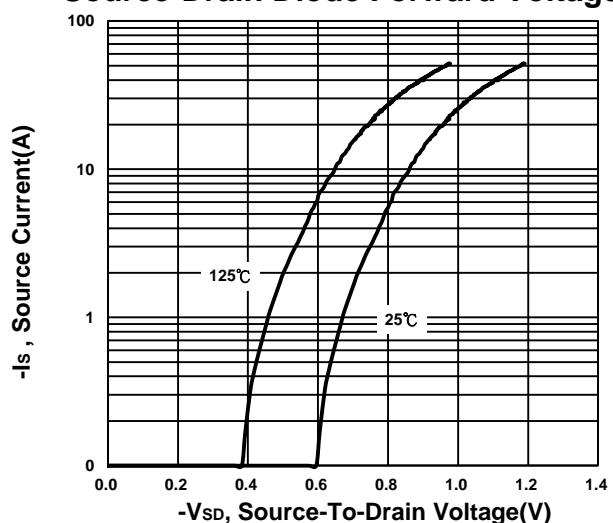
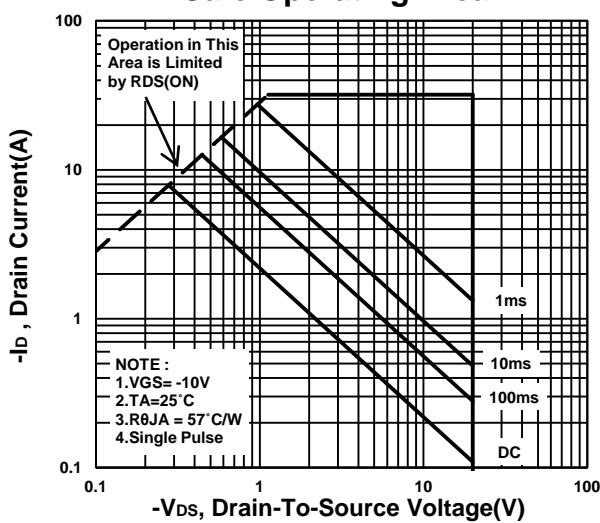
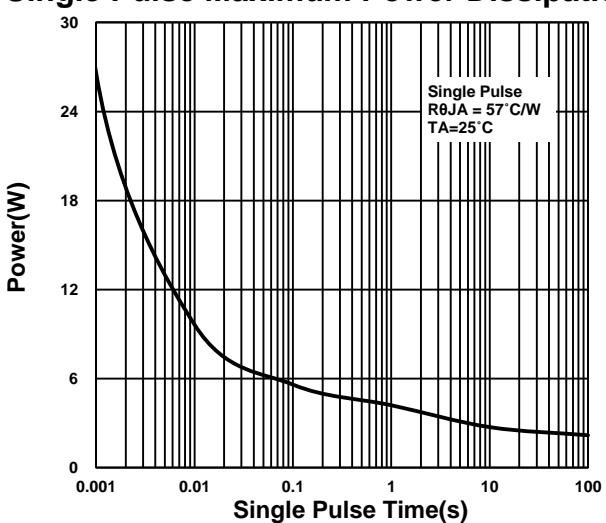


On-Resistance VS Gate-To-Source



On-Resistance VS Drain Current



NIKO-SEM**P-Channel Enhancement Mode
Field Effect Transistor****PB5B5BX
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Halogen-Free & Lead-Free****On-Resistance VS Temperature****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**